

3-Level NPC Inverter Module

NXH450N65L4Q2F2

The NXH450N65L4Q2F2 is a power module containing a I- type neutral point clamped three-level inverter. The integrated field stop trench IGBTs and FRDs provide lower conduction losses and switching losses, enabling designers to achieve high efficiency and superior reliability.

Features

- Neutral Point Clamped Three-Level Inverter Module
- 650 V Field Stop 4 IGBTs
- Low Inductive Layout
- Solderable Pins
- Thermistor

Typical Applications

- Solar Inverters
- Uninterruptable Power Supplies Systems

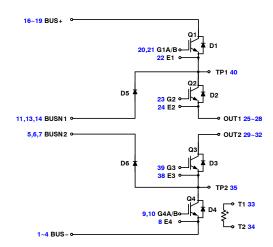
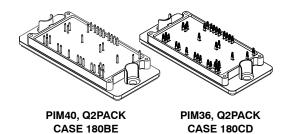


Figure 1. Schematic Diagram



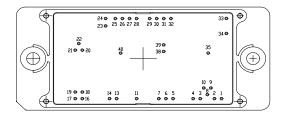
MARKING DIAGRAM NXH450N65L4Q2F2xG **ATYYWW**

NXH450N65L4Q2F2x = Specific Device Code

= Pb-Free Package

= Assembly & Test Site Code YYWW = Year and Work Week Code

PIN ASSIGNMENTS



ORDERING INFORMATION

See detailed ordering and shipping information in the dimensions section on page 5 of this data sheet.

Table 1. MAXIMUM RATINGS (Note 1)

Rating	Symbol	Value	Unit
OUTER IGBT (Q1-1, Q1-2, Q4-1, Q4-2)			•
Collector-Emitter Voltage	V _{CES}	650	V
Gate–Emitter Voltage Positive Transient Gate–Emitter Voltage (t_{pulse} = 5 μ s, D < 0.10)	V _{GE}	±20 30	V
Continuous Collector Current @ T _c = 80°C (T _J = 175°C)	I _C	167	А
Pulsed Collector Current (T _J = 175°C)	I _{Cpulse}	501	А
Maximum Power Dissipation ($T_J = 175^{\circ}C$)	P _{tot}	365	W
Maximum Operating Junction Temperature	T _{JMAX}	150	°C
NNER IGBT (Q2, Q3)			
Collector-Emitter Voltage	V _{CES}	650	V
Gate–Emitter Voltage Positive Transient Gate–Emitter Voltage (t_{pulse} = 5 μ s, D < 0.10)	V _{GE}	±20 30	V
Continuous Collector Current @ T _c = 80°C (T _J = 175°C)	Ic	280	Α
Pulsed Collector Current (T _J = 175°C)	I _{Cpulse}	840	А
Maximum Power Dissipation ($T_J = 175^{\circ}C$)	P _{tot}	633	W
Maximum Operating Junction Temperature	T _{JMAX}	150	°C
EUTRAL POINT DIODE (D5, D6)			
Peak Repetitive Reverse Voltage	V_{RRM}	650	V
Continuous Forward Current @ T _c = 80°C (T _J = 175°C)	I _F	271	Α
Repetitive Peak Forward Current (T _J = 175°C)	I _{FRM}	813	А
Maximum Power Dissipation (T _J = 175°C)	P _{tot}	559	W
Maximum Operating Junction Temperature	T _{JMAX}	150	°C
IVERSE DIODES (D1, D2, D3, D4)			
Peak Repetitive Reverse Voltage	V _{RRM}	650	V
Continuous Forward Current @ T _c = 80°C (T _J = 175°C)	I _F	131	А
Repetitive Peak Forward Current (t _p = 1 ms)	I _{FRM}	450	А
Maximum Power Dissipation ($T_J = 175^{\circ}C$)	P _{tot}	288	W
Maximum Operating Junction Temperature	T _{JMAX}	150	°C
HERMAL PROPERTIES			
Storage Temperature Range	T _{stg}	-40 to 150	°C
NSULATION PROPERTIES	_		-
Isolation Test Voltage, t = 1 s, 50 Hz	V _{is}	4000	V _{RMS}
Creepage Distance		12.7	mm

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

Table 2. RECOMMENDED OPERATING RANGES

Rating	Symbol	Min	Max	Unit
Module Operating Junction Temperature	T_J	-40	T_{JMAX}	°C

Functional operation above the stresses listed in the Recommended Operating Ranges is not implied. Extended exposure to stresses beyond the Recommended Operating Ranges limits may affect device reliability.

^{1.} Refer to ELECTRICAL CHĂRACTERISTICS, RECOMMENDED OPERATING RANGES and/or APPLICATION INFORMATION for Safe Operating parameters.

Table 3. ELECTRICAL CHARACTERISTICS (T_{.I} = 25°C unless otherwise noted)

Parameter	Test Conditions	Symbol	Min	Тур	Max	Unit
OUTER IGBT (Q1-1, Q1-2, Q4-1, Q4-2)						
Collector-Emitter Cutoff Current	V _{GE} = 0 V, V _{CE} = 650 V	I _{CES}	_	_	300	μΑ
Collector-Emitter Saturation Voltage	V _{GE} = 15 V, I _C = 225 A, T _J = 25°C	o°C V _{CE(sat)} –		1.49	2.2	V
	V _{GE} = 15 V, I _C = 225 A, T _J = 150°C		_	1.70	-	1
Gate-Emitter Threshold Voltage	$V_{GE} = V_{CE}, I_{C} = 2.25 \text{ mA}$	V _{GE(TH)}	3.1	4.0	5.2	V
Gate Leakage Current	V _{GE} = 20 V, V _{CE} = 0 V	I _{GES}	-	-	600	nA
Turn-on Delay Time	T _J = 25°C	t _{d(on)}	-	163	-	ns
Rise Time	$V_{CE} = 400 \text{ V}, I_{C} = 100 \text{ A}$	t _r	-	45	-	1
Turn-off Delay Time	V_{GE} = -5 V to +15 V, $R_{G(on)}$ = 15 Ω , $R_{G(off)}$ = 15 Ω	t _{d(off)}	_	831	-	1
Fall Time		t _f	_	61	-	1
Turn-on Switching Loss per Pulse		E _{on}	=	2.344	=	mJ
Turn off Switching Loss per Pulse		E _{off}	=	3.125	=	1
Turn-on Delay Time	T _J = 125°C	t _{d(on)}	-	141	-	ns
Rise Time	$V_{CE} = 400 \text{ V}, I_{C} = 100 \text{ A}$	t _r	=	51	=	1
Turn-off Delay Time	V_{GE} = -5 V to +15 V, $R_{G(on)}$ = 15 Ω , $R_{G(off)}$ = 15 Ω	t _{d(off)}	-	898	-	1
Fall Time		t _f	=	80	=	1
Turn-on Switching Loss per Pulse		E _{on}	-	3.75	-	mJ
Turn off Switching Loss per Pulse		E _{off}	-	2.97	-	1
Input Capacitance	V _{CE} = 20 V, V _{GE} = 0 V, f = 10 kHz	C _{ies}	-	14630	-	pF
Output Capacitance		C _{oes}	=	230	=	
Reverse Transfer Capacitance		C _{res}	=	64	=	1
Total Gate Charge	V _{CE} = 480 V, I _C = 225 A, V _{GE} = 0~+15 V	Qg	=	452	-	nC
Thermal Resistance - Chip-to-Heatsink	Thermal grease,	R_{thJH}	=	0.45	=	°C/W
Thermal Resistance - Chip-to-Case	Thickness = 2 Mil $\pm 2\%$, $\lambda = 2.8$ W/mK	R _{thJC}	=	0.26	=	°C/W
NEUTRAL POINT DIODE (D5, D6)				•		<u>. </u>
Diode Forward Voltage	I _F = 375 A, T _J = 25°C	V _F	=	1.80	2.3	V
	I _F = 375 A, T _J = 150°C		-	1.77	-	1
Reverse Recovery Time	T _J = 25°C	t _{rr}	-	46	-	ns
Reverse Recovery Charge	$V_{CE} = 400 \text{ V}, I_{C} = 100 \text{ A}$	Q _{rr}	=	1.5	-	μC
Peak Reverse Recovery Current	$V_{GE} = -5 \text{ V to } +15 \text{ V}, R_G = 15 \Omega$	I _{RRM}	-	53	-	Α
Peak Rate of Fall of Recovery Current		di/dt	-	2541	-	A/μs
Reverse Recovery Energy		E _{rr}	-	0.3	-	mJ
Reverse Recovery Time	T _J = 125°C	t _{rr}	_	75	_	ns
Reverse Recovery Charge	$V_{CE} = 400 \text{ V}, I_{C} = 100 \text{ A}$	Q _{rr}	_	4	-	μС
Peak Reverse Recovery Current	$V_{GE} = -5 \text{ V to } +15 \text{ V}, R_G = 15 \Omega$	I _{RRM}	-	96	_	Α
Peak Rate of Fall of Recovery Current		di/dt	_	2500	_	A/μs
Reverse Recovery Energy		E _{rr}	_	0.83	_	mJ
Thermal Resistance - Chip-to-Heatsink	Thermal grease,	R _{thJH}	_	0.37	_	°C/W
Thermal Resistance - Chip-to-Case	Thickness = 2 Mil $\pm 2\%$, λ = 2.8 W/mK	R _{thJC}	_	0.17	_	°C/W

Table 3. ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise noted) (continued)

Parameter	Test Conditions	Symbol	Min	Тур	Max	Unit
INNER IGBT (Q2, Q3)		•		•		•
Collector-Emitter Cutoff Current	V _{GE} = 0 V, V _{CE} = 650 V	I _{CES}	-	_	300	μΑ
Collector-Emitter Saturation Voltage	V _{GE} = 15 V, I _C = 375 A, T _J = 25°C	V _{CE(sat)}	_	1.49	2.2	٧
	V _{GE} = 15 V, I _C = 375 A, T _J = 150°C	1 1	=	1.72	=	1
Gate-Emitter Threshold Voltage	$V_{GE} = V_{CE}$, $I_C = 3.75$ mA	V _{GE(TH)}	3.1	4.1	5.2	V
Gate Leakage Current	V _{GE} = 20 V, V _{CE} = 0 V	I _{GES}	_	-	1000	nA
Turn-on Delay Time	T _J = 25°C	t _{d(on)}	_	134	_	ns
Rise Time	$V_{CE} = 400 \text{ V}, I_{C} = 100 \text{ A}$	t _r	_	47	_	
Turn-off Delay Time	V_{GE} = -5 V to +15 V, $R_{G(on)}$ = 15 Ω , $R_{G(off)}$ = 15 Ω	t _{d(off)}	_	709	_	
Fall Time	1	t _f	_	32	_	1
Turn-on Switching Loss per Pulse		E _{on}	=	1.72	_	mJ
Turn off Switching Loss per Pulse		E _{off}	=	2.65	=	1
Turn-on Delay Time	T _J = 125°C	t _{d(on)}	=	118	=	ns
Rise Time	V _{CE} = 400 V, I _C = 100 A	t _r	=	52	=	1
Turn-off Delay Time	V_{GE} = -5 V to +15 V, $R_{G(on)}$ = 15 Ω , $R_{G(off)}$ = 15 Ω	t _{d(off)}	=	765	=	1
Fall Time		t _f	-	29	-	1
Turn-on Switching Loss per Pulse		E _{on}	-	2.34	-	mJ
Turn off Switching Loss per Pulse		E _{off}	-	2.89	-	1
Input Capacitance	V _{CE} = 20 V, V _{GE} = 0 V, f = 10 kHz	C _{ies}	=	24383	=	pF
Output Capacitance		C _{oes}	=	383	=	1
Reverse Transfer Capacitance	7	C _{res}	_	105	_	
Total Gate Charge	V _{CE} = 480 V, I _C = 375 A, V _{GE} = 0~+15 V	Q_g	_	753	_	nC
Thermal Resistance - Chip-to-Heatsink	Thermal grease,	R_{thJH}	_	0.31	_	°C/W
Thermal Resistance - Chip-to-Case	Thickness = 2 Mil $\pm 2\%$, $\lambda = 2.8$ W/mK	R _{thJC}	_	0.15	_	°C/W
INVERSE DIODES (D1, D2, D3, D4)				•	•	
Diode Forward Voltage	I _F = 150 A, T _J = 25°C	V _F	-	1.78	2.3	٧
	I _F = 150 A, T _J = 150°C		-	1.77	_	
Reverse Recovery Time	T _J = 25°C	t _{rr}	-	43	_	ns
Reverse Recovery Charge	$V_{CE} = 400 \text{ V}, I_{C} = 100 \text{ A}$	Q _{rr}	-	1.14	_	μC
Peak Reverse Recovery Current	V_{GE} = -5 V to +15 V, R_{G} = 15 Ω	I _{RRM}	_	46	_	Α
Peak Rate of Fall of Recovery Current		di/dt	=	2473	=	A/μs
Reverse Recovery Energy		E _{rr}	_	0.313	_	mJ
Reverse Recovery Time	T _J = 125°C	t _{rr}	=	67	_	ns
Reverse Recovery Charge	V _{CE} = 400 V, I _C = 100 A	Q _{rr}	=	2.5	=	μC
Peak Reverse Recovery Current	V_{GE} = -5 V to +15 V, R_{G} = 15 Ω	I _{RRM}	=	66	=	Α
Peak Rate of Fall of Recovery Current		di/dt	=	2317	-	A/μs
Reverse Recovery Energy		E _{rr}	=	0.625	=	mJ
Thermal Resistance - Chip-to-Heatsink	Thermal grease,	R_{thJH}	_	0.58	_	°C/W
Thermal Resistance - Chip-to-Case	Thickness = 2 Mil $\pm 2\%$, λ = 2.8 W/mK	R _{thJC}	-	0.33	_	°C/W

Table 3. ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise noted) (continued)

Parameter	Test Conditions	Symbol Min		Тур	Max	Unit		
THERMISTOR CHARACTERISTICS								
Nominal Resistance	T = 25°C	R ₂₅	-	22	_	kΩ		
Nominal Resistance	T = 100°C	R ₁₀₀	=	1486	-	Ω		
Deviation of R25		ΔR/R	-5	_	5	%		
Power Dissipation		P_{D}	=	200	-	mW		
Power Dissipation Constant			=	2	-	mW/K		
B-value	B(25/50), tolerance ±3%		=	3950	=	K		
B-value	B(25/100), tolerance ±3%		_	3998	_	K		

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

ORDERING INFORMATION

Orderable Part Number	Marking	Package	Shipping
NXH450N65L4Q2F2SG	NXH450N65L4Q2F2SG	PIM40, Q2PACK (Pb-Free and Halide-Free)	12 Units / Blister Tray
NXH450N65L4Q2F2PG	NXH450N65L4Q2F2PG	PIM436 Q2PACK (Pb-Free and Halide-Free)	12 Units / Blister Tray

TYPICAL CHARACTERISTICS - IGBT Q1-1, Q1-2, Q4-1, Q4-2 AND DIODE D1, D4

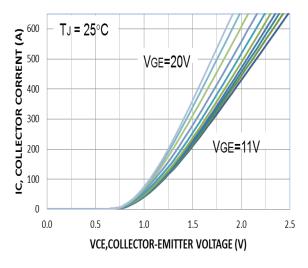


Figure 2. Typical Output Characteristics

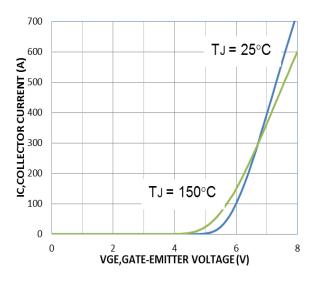


Figure 4. Typical Transfer Characteristics

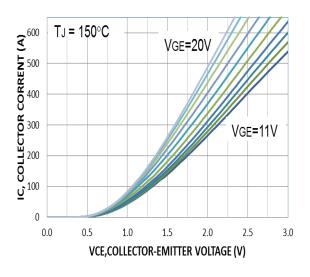


Figure 3. Typical Output Characteristics

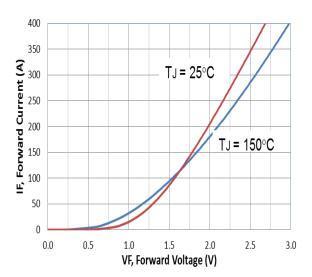


Figure 5. Typical Transfer Characteristics

TYPICAL CHARACTERISTICS - IGBT Q1-1, Q1-2, Q4-1, Q4-2 AND DIODE D1, D4

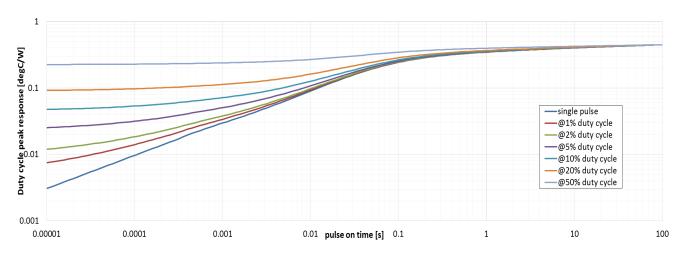


Figure 6. Transient Thermal Impedance (Q1-1, Q1-2, Q4-1, Q4-2)

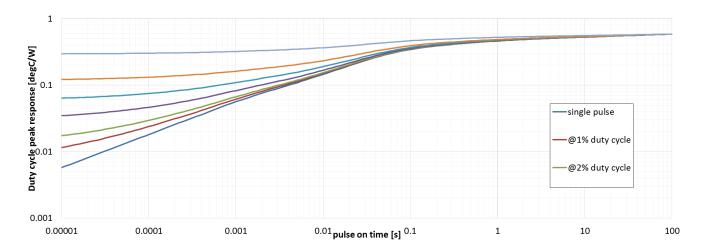


Figure 7. Transient Thermal Impedance (D1, D4)

TYPICAL CHARACTERISTICS - IGBT Q1-1, Q1-2, Q4-1, Q4-2 AND DIODE D1, D4

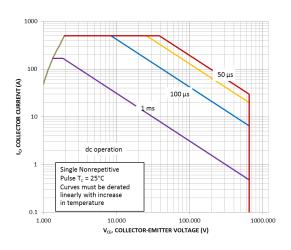


Figure 8. FBSOA (Q1-1, Q1-2, Q4-1, Q4-2)

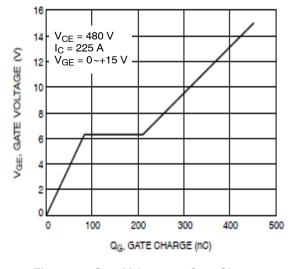


Figure 10. Gate Voltage vs. Gate Charge

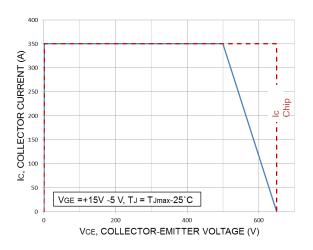


Figure 9. RBSOA (Q1-1, Q1-2, Q4-1, Q4-2)

TYPICAL CHARACTERISTICS - IGBT Q2, Q3 AND DIODE D2, D3

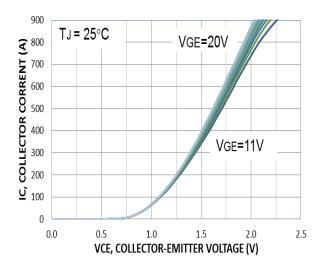


Figure 11. Typical Output Characteristics

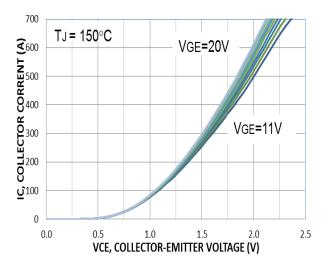


Figure 12. Typical Output Characteristics

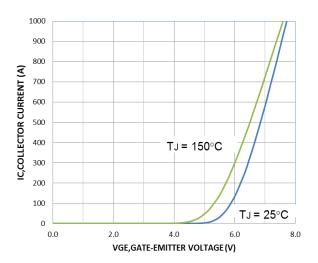


Figure 13. Typical Transfer Characteristics

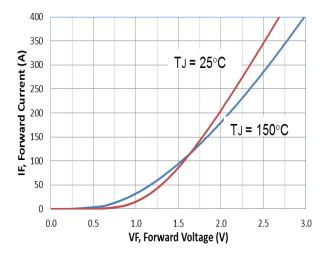


Figure 14. Typical Transfer Characteristics

TYPICAL CHARACTERISTICS - IGBT Q2, Q3 AND DIODE D2, D3

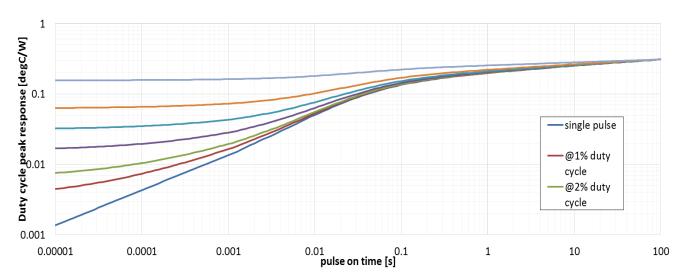


Figure 15. Transient Thermal Impedance (Q2, Q3)

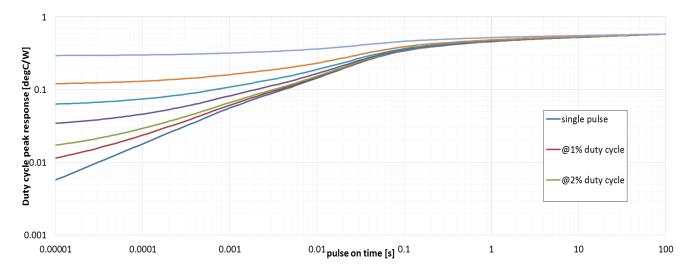


Figure 16. Transient Thermal Impedance (D2, D3)

TYPICAL CHARACTERISTICS - IGBT Q2, Q3 AND DIODE D2, D3

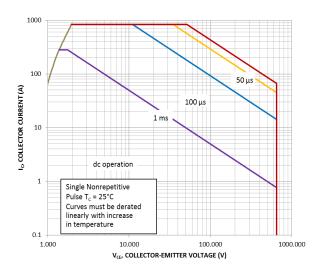


Figure 17. FBSOA (Q2, Q3)

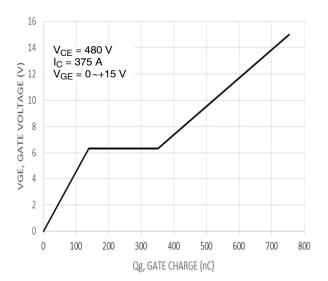


Figure 19. Gate Voltage vs. Gate Charge

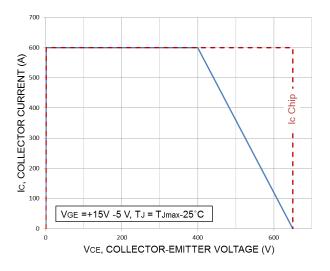


Figure 18. RBSOA (Q2, Q3)

TYPICAL CHARACTERISTICS - DIODE D5, D6

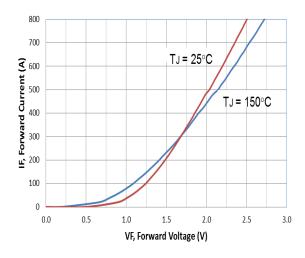


Figure 20. Diode Forward Characteristics

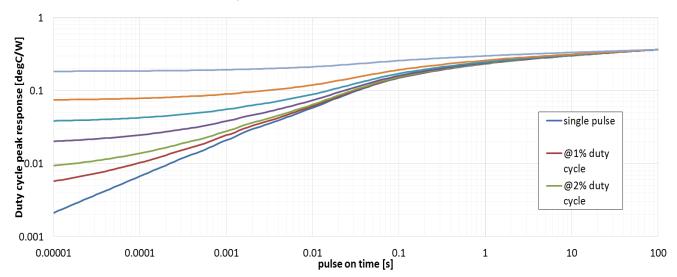


Figure 21. Transient Thermal Impedance (D5, D6)

TYPICAL CHARACTERISTICS - Q1/Q4 IGBT COMUTATES D5/D6 DIODE

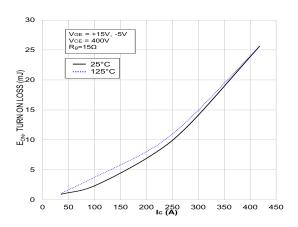


Figure 22. Typical Switching Loss Eon vs. IC

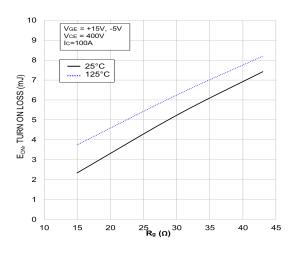


Figure 24. Typical Switching Loss Eon vs. R_G

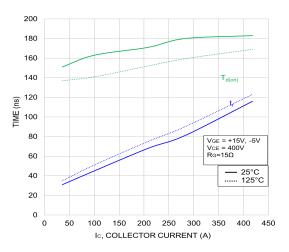


Figure 26. Typical Switching Time Tdon vs. IC

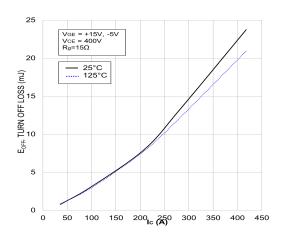


Figure 23. Typical Switching Loss Eoff vs. IC

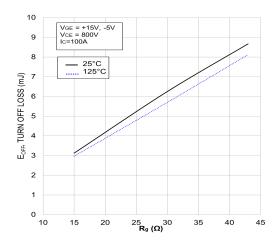


Figure 25. Typical Switching Loss Eoff vs. R_G

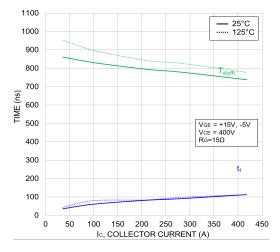


Figure 27. Typical Switching Time Tdoff vs. IC

TYPICAL CHARACTERISTICS - Q1/Q4 IGBT COMUTATES D5/D6 DIODE

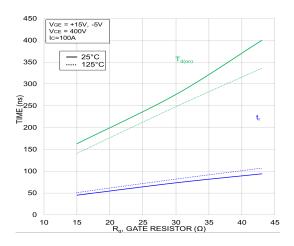


Figure 28. Typical Switching Time Tdon vs. R_G

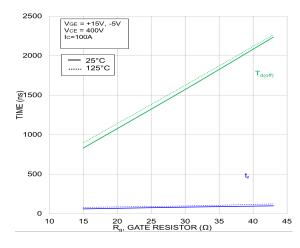


Figure 29. Typical Switching Time Tdoff vs. R_G

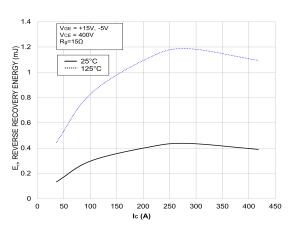


Figure 30. Typical Reverse Recovery Energy vs. IC

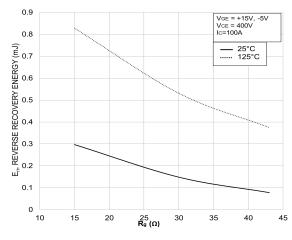


Figure 31. Typical Reverse Recovery Energy vs. R_G

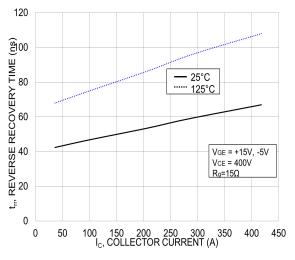


Figure 32. Typical Reverse Recovery Time vs. IC

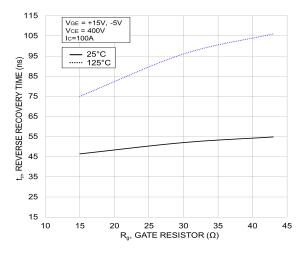


Figure 33. Typical Reverse Recovery Time vs. R_G

TYPICAL CHARACTERISTICS - Q1/Q4 IGBT COMUTATES D5/D6 DIODE

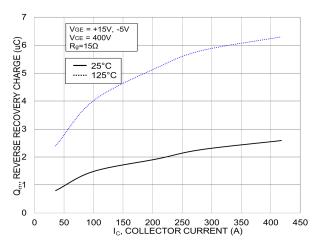


Figure 34. Typical Reverse Recovery Charge vs. IC

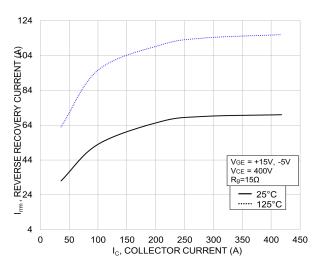


Figure 36. Typical Reverse Recovery Current vs. IC

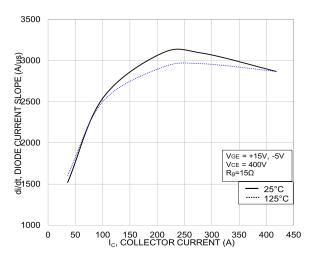


Figure 38. Typical di/dt vs. IC

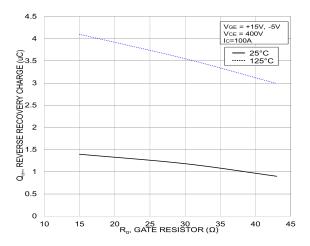


Figure 35. Typical Reverse Recovery Charge vs. R_G

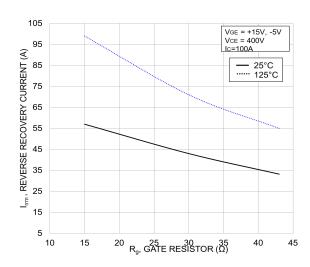


Figure 37. Typical Reverse Recovery Current vs. R_G

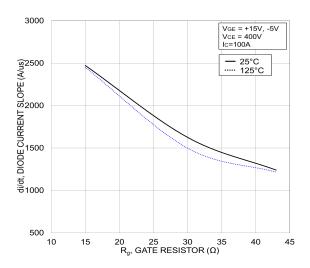


Figure 39. Typical di/dt vs. R_G

TYPICAL CHARACTERISTICS - Q2/Q3 IGBT COMUTATES D1/D4 DIODE

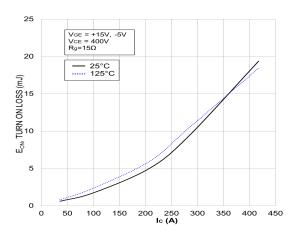


Figure 40. Typical Switching Loss Eon vs. IC

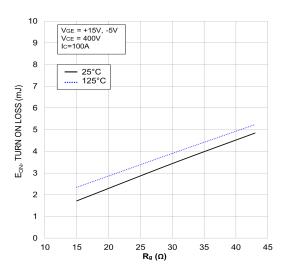


Figure 42. Typical Switching Loss Eon vs. R_G

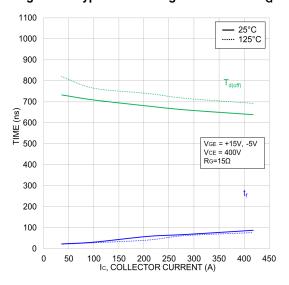


Figure 44. Typical Turn-On Switching Time vs. IC

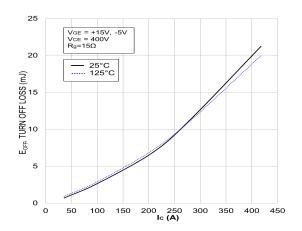


Figure 41. Typical Switching Loss Eoff vs. IC

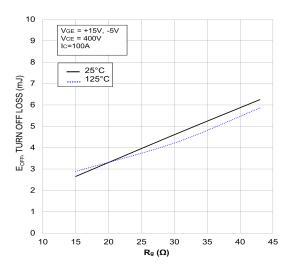


Figure 43. Typical Switching Loss Eoff vs. $R_{\mbox{\scriptsize G}}$

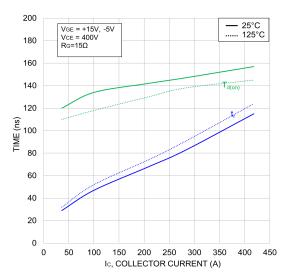


Figure 45. Typical Turn-Off Switching Time vs. IC

TYPICAL CHARACTERISTICS - Q2/Q3 IGBT COMUTATES D1/D4 DIODE

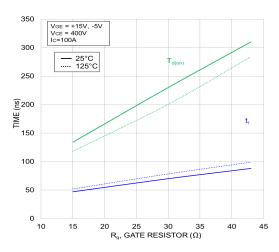


Figure 46. Typical Turn-On Switching Time vs. R_G

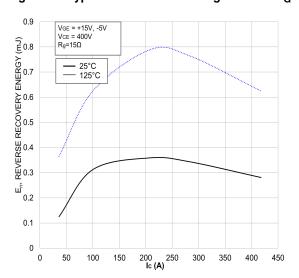


Figure 48. Typical Reverse Recovery Energy Loss vs. IC

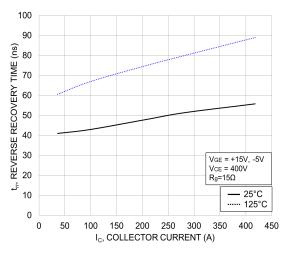


Figure 50. Typical Reverse Recovery Time vs. IC

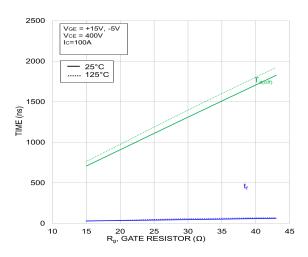


Figure 47. Typical Turn-Off Switching Time vs. R_G

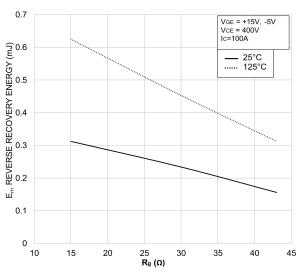


Figure 49. Typical Reverse Recovery Energy Loss vs. R_G

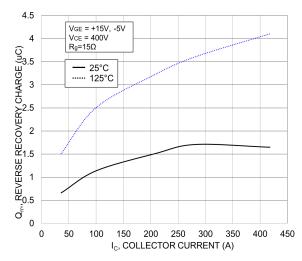


Figure 51. Typical Reverse Recovery Charge vs. IC

TYPICAL CHARACTERISTICS - Q2/Q3 IGBT COMUTATES D1/D4 DIODE

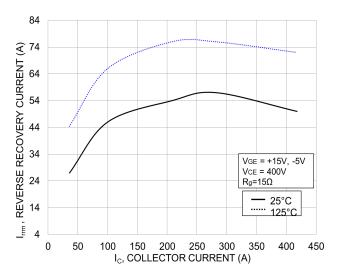


Figure 52. Typical Reverse Recovery Current vs. IC

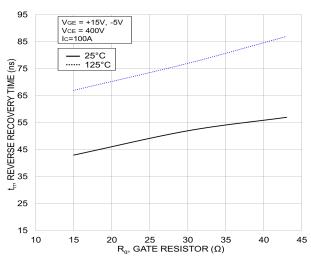


Figure 54. Typical Reverse Recovery Time vs. R_G

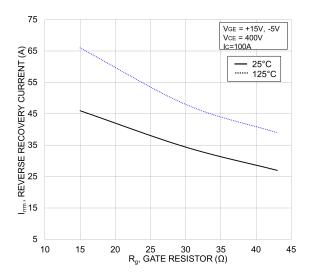


Figure 56. Typical Reverse Recovery Peak Current vs. R_G

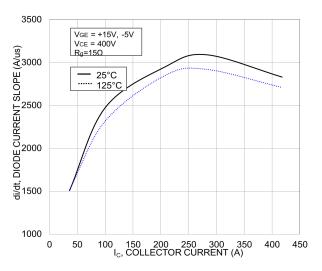


Figure 53. Typical di/dt Current Slope vs. IC

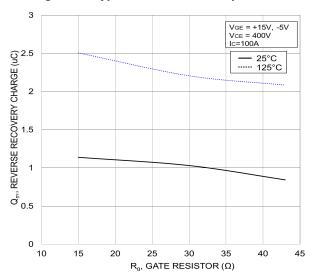


Figure 55. Typical Reverse Recovery Charge vs. R_G

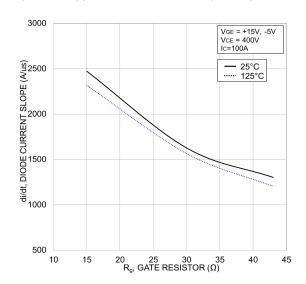
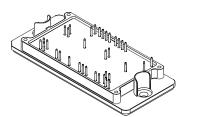


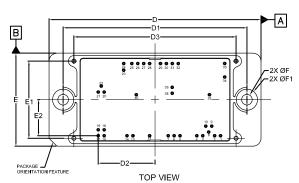
Figure 57. Typical di/dt vs. R_G

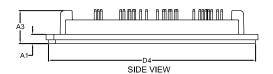


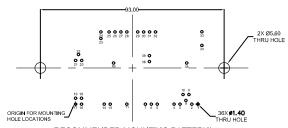


PIM40, 107.2x47 CASE 180BE ISSUE C

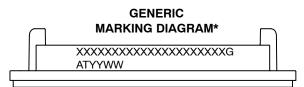
DATE 27 JUL 2022







RECOMMENDED MOUNTING PATTERN*
For additional information on our Pb-Free strategy and soldering details, please download the On Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.



XXXXX = Specific Device Code

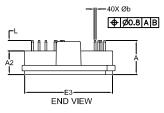
G = Pb-Free Package

AT = Assembly & Test Site Code

YYWW = Year and Work Week Code

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "•", may or may not be present. Some products may not follow the Generic Marking.

	MILLIMETERS					
DIM	MIN.	NOM.	MAX.			
Α	16.63	17.23	17.83			
A1	4.50	4.70	4.90			
A2	11.60	12.00	12.40			
A3	16.40	16.70	17.00			
b	0.95	1.00	1.05			
D	106.80	107.20	107.60			
D1	92.90	93.00	93.10			
D2	28.40	28.70	29.00			
D3	81.80	82.00	82.20			
D4	104.35	104.75	105.15			
E	46.60	47.00	47.40			
E1	38.80	39.00	39.20			
E2	17.95	18.25	18.55			
E3	44.30	44.40	44.50			
F	5.40	5.50	5.60			
F1	10.70 REF					
L	5.03	5.23	5.43			



NOTE 4

	PIN POS	SITION		PIN POS	SITION
PIN	Х	Υ	PIN	Х	Υ
1	61.85	0.0	21	0.0	22.1
2	58.85	0.0	22	1.5	25.1
3	52.85	0.0	23	12.85	33.15
4	49.85	0.0	24	12.85	36.5
5	41.35	0.0	25	16.95	36.5
6	38.35	0.0	26	19.95	36.5
7	35.35	0.0	27	22.95	36.5
8	55.85	1.85	28	25.95	36.5
9	57.35	4.85	29	31.45	36.5
10	54.35	4.85	30	34.45	36.5
11	25.95	0.0	31	37.45	36.5
13	17.5	0.0	32	40.45	36.5
14	14.5	0.0	33	63.9	36.55
16	3.0	0.0	34	63.9	29.7
17	0.0	0.0	35	56.2	20.75
18	3.0	3.0	38	37.4	21.5
19	0.0	3.0	39	37.4	24.5
20	3.0	22.1	40	19.2	20.75

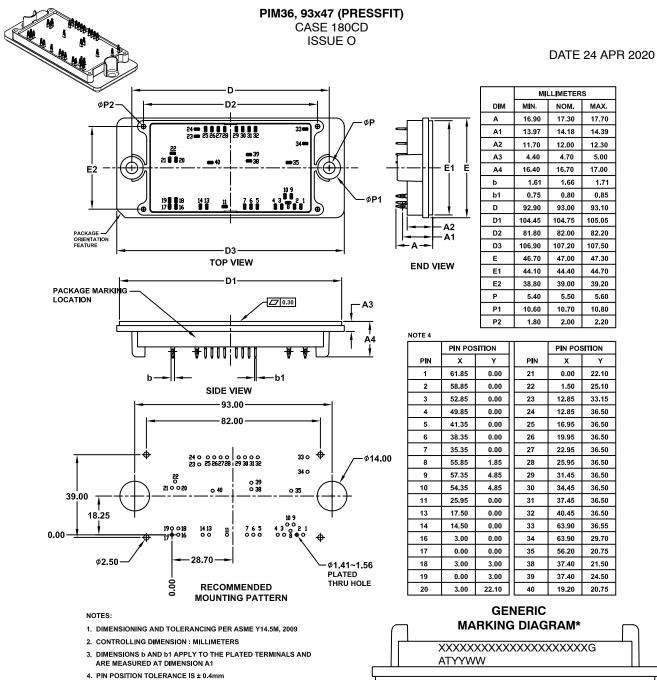
NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME 7 14.5M, 2009.
- 2. CONTROLLING DIMENSION: MILLIMETERS
- 3. DIMENSIONS 6 APPLY TO THE PLATED TERMINALS AND ARE MEASURED WHERE THE PIN EXITS THE PACKAGE BODY.
- POSITION OF THE CENTER OF THE TERMINALS IS DETERMINED FROM PIN 17. POSITIONAL TOLERANCE, AS NOTED IN THE DRAWING, APPLIES TO EACH TERMINAL.

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DESCRIPTION:	PIM40, 107.2x47		PAGE 1 OF 1

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5. PACKAGE MARKING IS LOCATED AS SHOWN ON THE SIDE OPPOSITE THE PACKAGE ORIENTATION FEATURES

XXXXX = Specific Device Code G = Pb-Free Package = Assembly & Test Site Code AT YYWW= Year and Work Week Code

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot " • ", may or may not be present. Some products may not follow the Generic Marking.

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DESCRIPTION:	PIM36 93X47 (PRESS FIT)		PAGE 1 OF 1

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